

SUBSTITUTE FORM PTO-1449
(MODIFIED)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET
07977/124004 124003

SERIAL NO.
08/802,276-09/995549

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(Use several sheets if necessary)

APPLICANT:
Yamazaki, et al.

FILING DATE
February 19, 1997 11/27/01

GROUP ART UNIT
2813-2825

(37 CFR 1.98(b))

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5	4	0	3	7	7	2	4/4/95	Zhang et al.	437	101	
	AB	5	4	2	6	0	6	4	6/20/95	Zhang et al.	437	40	
	AC	5	4	8	1	1	2	1	1/2/96	Zhang et al.	257	64	
	AD	5	4	8	8	0	0	0	1/30/96	Zhang et al.	437	21	
	AE	5	4	9	2	8	4	3	2/20/96	Adachi et al.	437	21	
	AF	5	5	0	1	9	8	9	3/26/96	Takayama et al.	437	21	
	AG	5	5	0	8	5	3	3	4/16/96	Takemura	257	64	
	AH	5	5	2	9	9	3	7	6/25/96	Zhang et al.	437	10	
	AI	5	5	3	4	7	1	6	7/9/96	Takemura	257	72	
	AJ	5	5	4	3	3	5	2	8/6/96	Ohtani et al.	437	101	
	AK	5	5	6	3	4	2	6	10/8/96	Zhang et al.	257	66	
	AL	5	5	6	9	6	1	0	10/29/96	Zhang et al.	437	21	
	AM	5	5	6	9	9	3	6	10/29/96	Zhang et al.	257	66	
	AN	5	5	8	0	7	9	2	12/3/96	Zhang et al.	437	10	
	AO	5	5	8	5	2	9	1	12/17/96	Ohtani et al.	437	40	
	AP	5	5	8	9	6	9	4	12/31/96	Takayama et al.	257	67	
	AQ	5	5	9	5	9	2	3	1/21/97	Zhang et al.	437	41	
	AR	5	5	9	5	9	4	4	1/21/97	Zhang et al.	437	41	
	AS	5	6	0	4	3	6	0	2/18/97	Zhang et al.	257	72	
	AT	5	6	0	5	8	4	6	2/25/97	Ohtani et al.	437	21	
	AU	5	6	0	6	1	7	9	2/25/97	Yamazaki et al.	257	59	
	AV	5	6	0	8	2	3	2	3/4/97	Yamazaki et al.	257	66	
	AW	5	6	1	2	2	5	0	3/18/97	Ohtani et al.	437	101	
	AX	5	6	1	4	4	2	6	3/25/97	Funada et al.	437	40	
	AY	5	6	1	4	7	3	3	3/35/97	Zhang et al.	257	66	
	AZ	5	6	1	6	5	0	6	4/1/97	Takemura	438	150	
		5	6	2	0	9	1	0	4/15/97	Teramoto	438	151	
	BA	5	6	2	1	2	2	4	4/15/97	Yamazaki et al.	257	66	
	BB	5	6	2	4	8	5	1	4/29/97	Takayama et al.	438	166	
	BC	5	6	3	7	5	1	5	6/10/97	Takemura	438	162	
	BD	5	6	3	9	6	9	8	6/17/97	Yamazaki et al.	437	228	

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EXAMINER INITIAL	PATENT NUMBER							ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA	5	8	4	9	6	0	1	12/15/98	Shunpei Yamazaki	437	101	<div>JP0857 U.S. PTO 09/995549</div> <div>11/27/01</div>
AB	5	8	5	8	8	2	3	1/12/99	Yamazaki, et al.	438	166	
AC	5	8	8	6	3	6	6	3/23/99	Yamazaki, et al.	257	59	
AD	5	8	9	3	7	3	0	4/13/99	Yamazaki, et al.	438	166	
AE												
AF												
AG												
AH												
AI												
AJ												
AK												

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

		DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
AL	JP 6-232059	8/19/94	Japan				X	
AM	JP 06-244103	9/2/94	Japan				Abstract only	X
AN								
AO								
AP								

OTHER DOCUMENTS (including Author, Title, Date, Place of Publication)

AQ	Shimokawa, et al., "Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement", Japanese Journal of Applied Physics Vol. 27, No. 5, pp.751-758, May 1988.
AR	
AS	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-124003	Application No. 09/995,549
	Applicant Shunpei Yamazaki et al.		
	Filing Date November 27, 2001	Group Art Unit 2825	

U.S. Patent Documents

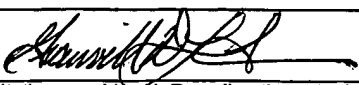
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,529,937	06/25/1996	Zhang et al.			07/20/1994
	AB	5,643,826	07/01/1997	Ohtani et al.			10/25/1994
	AC	5,696,003	12/09/1997	Makita et al.			12/16/1994
	AD	5,821,562	10/13/1998	Makita et al.			05/30/1995
	AE	5,923,962	07/13/1999	Ohtani et al.			04/28/1995
	AF	6,285,042	09/04/2001	Ohtani et al.			09/12/1997
	AG	6,335,541	01/01/2002	Ohtani et al.			04/15/1996

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AH	0 481 777 A2	04/22/1992	EUROPE			IN ENGLISH	
	AI	0 651 431 A2	05/03/1995	EUROPE			IN ENGLISH	
	AJ	1992-0008930	05/28/1992	KOREA			ABS	
	AK	1995-0004453	02/18/1995	KOREA			ABS	
	AL	1995-0012580	05/16/1995	KOREA			ABS	
	AM	1995-0021777	07/26/1995	KOREA			ABS	

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AN	
	AO	
	AP	
	AQ	
	AR	
	AS	
	AT	
	AU	

Examiner Signature 	Date Considered 02/31/04
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	